

FIG. 1

(method of generating test sequence for delay fault)

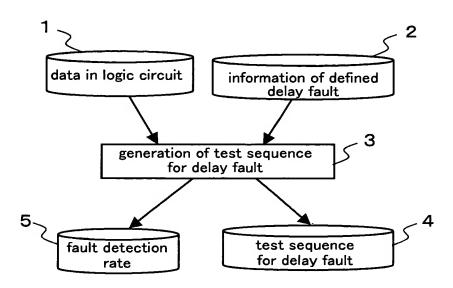


FIG. 2 (method of simulating delay fault)

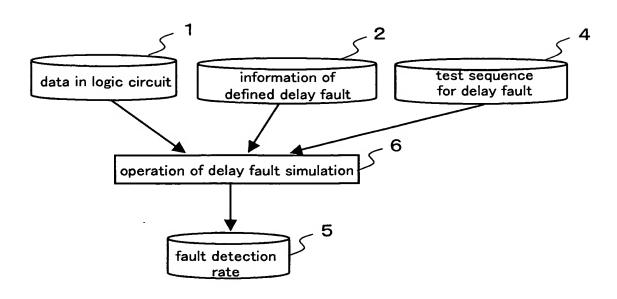


FIG. 3

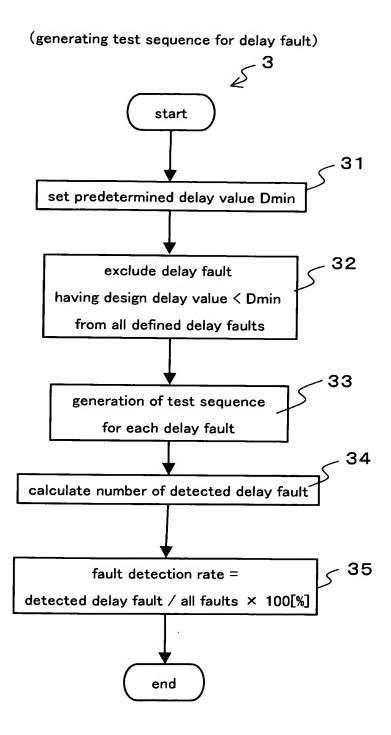
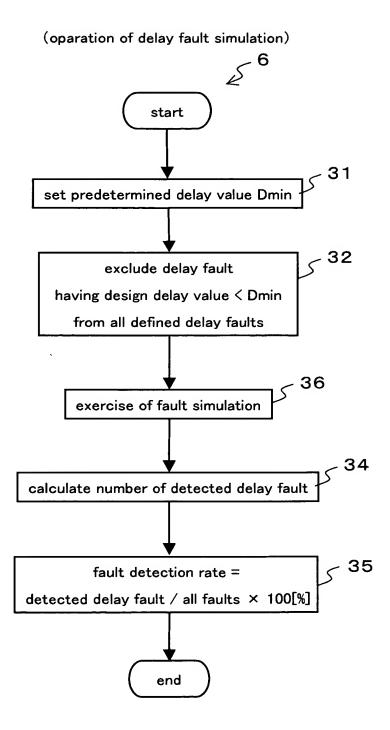
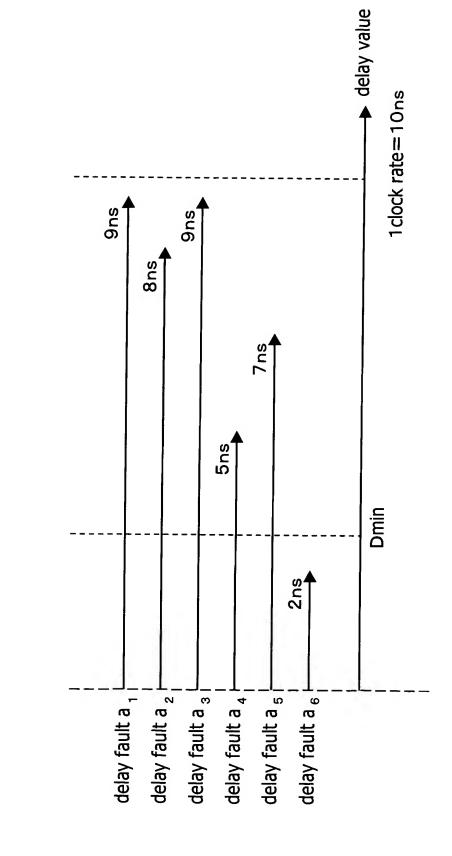


FIG. 4

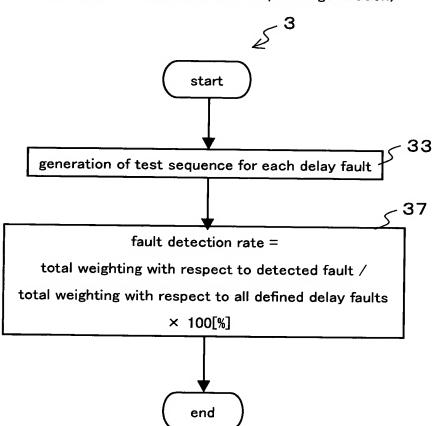


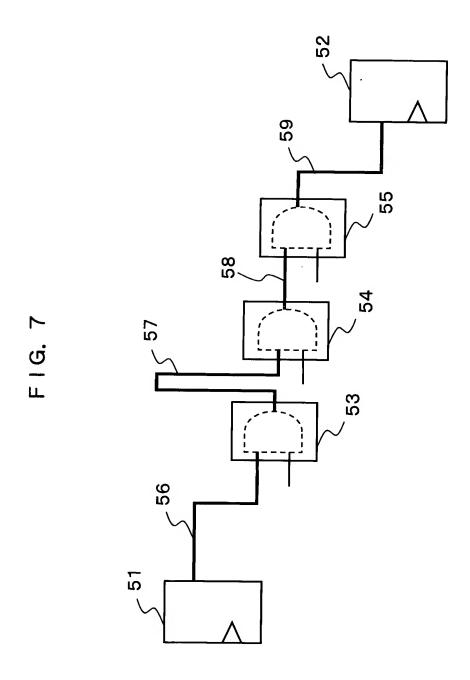


F I G. 5

FIG. 6

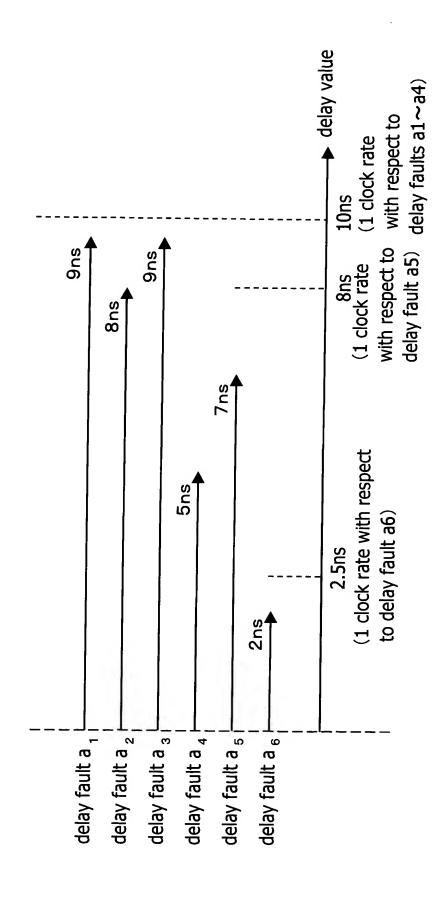
(operation of delay-fault test sequence generation)





F I G. 8

F I G. 9



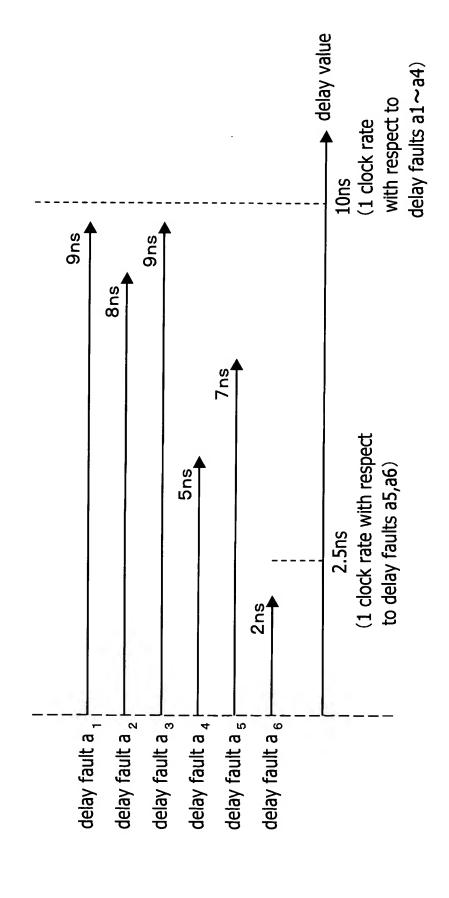


FIG. 11

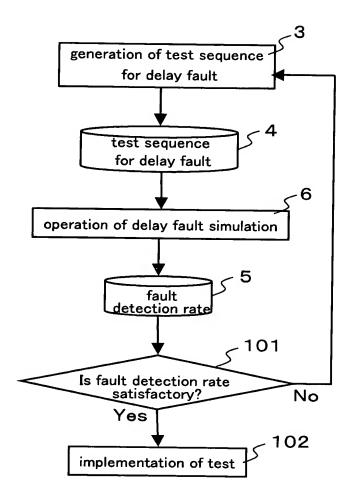
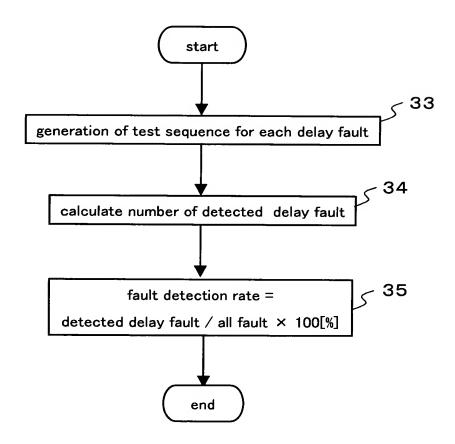


FIG. 13 PRIOR ART



→ delay value 1 clock rate signal path b₂ signal path b₃ l signal path b4 signal path b, l signal path b_{s |} signal path be

FIG. 14 PRIOR ART